

Model: Micron_1300_MTFD

S/N: 21032D566B5E

Disk Erasure Report

Page 1 - Erasure Status



Organisation Performing The Disk Erasure

Business Name: Not Applicable (BN)

Business Address: Not Applicable (BA)

Contact Name: Not Applicable (BCN)

Contact Phone: Not Applicable (BCP)

Customer Details

Name: Not Applicable (CN)

Address: Not Applicable (CA)

Contact Name: Not Applicable (CCN)

Contact Phone: Not Applicable (CP)

Disk Information

Make/Model: Micron_1300_MTFD

Serial: 21032D566B5E

Size(Apparent): 2048 GB, 2048408248320 bytes

Bus: ATA-SSD

Size(Real): 2048 GB, 2048408248320 bytes

Disk Erasure Details

Start time: 2025/02/23 06:23:15

End time: 2025/02/23 06:31:24

Duration: 00:08:09

Status: **FAILED**

Method: PRNG Stream

PRNG algorithm: XORshiro256

Final Pass(Zeros/Ones/None): Zeros

Verify Pass(Last/All/None): Verify Last

*Bytes Erased: 31539200000, (1.53%)

Rounds(completed/requested): 0/1

HPA/DCO: No hidden sectors

HPA/DCO Size: No hidden sectors

Errors(pass/sync/verify): 1/1/0

Throughput: 64 MB/sec

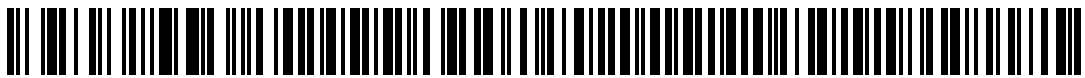
Information:

* bytes erased: The amount of drive that's been erased at least once

Technician/Operator ID

Signature:

Name/ID: Not Applicable (OTN)



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smartctl 7.2 2020-12-30 r5155 [x86_64-linux-5.14.0-503.23.1.el9_5.x86_64] (local build)
copyright (c) 2002-20, bruce allen, christian franke, www.smartmontools.org

=== start of information section ===

model family: Crucial/Micron Client SSDs
device model: Micron_1300_MTFDDAK2T0TDL
serial number: 21032D566B5E
lu wwn device id: 5 00a075 12d566b5e
firmware version: M5MU030
user capacity: 2,048,408,248,320 bytes [2.04 TB]
sector size: 512 bytes logical/physical
rotation rate: Solid State Device
form factor: 2.5 inches
trim command: Available, deterministic, zeroed
device is: In smartctl database [for details use: -P show]
ata version is: ACS-4 T13/BSR INCITS 529 revision 5
sata version is: SATA 3.3, 6.0 Gb/s (current: 6.0 Gb/s)
local time is: Sun Feb 23 06:31:26 2025 GMT
smart support is: Available - device has SMART capability.
smart support is: Enabled

=== start of read smart data section ===

smart overall-health self-assessment test result: FAILED!
drive failure expected in less than 24 hours. save all data.
no failed attributes found.

general smart values:

offline data collection status: (0x00)Offline data collection activity
was never started.
auto offline data collection: Disabled.
self-test execution status: (0)The previous self-test routine completed
without error or no self-test has ever
been run.
total time to complete offline
data collection: (5428) seconds.
offline data collection
capabilities: (0x7b) SMART execute Offline immediate.
auto offline data collection on/off support.
suspend offline collection upon new
command.
offline surface scan supported.
self-test supported.
conveyance self-test supported.
selective self-test supported.
smart capabilities: (0x0003)Saves SMART data before entering
power-saving mode.
supports smart auto save timer.
error logging capability: (0x01)Error logging supported.
general purpose logging supported.
short self-test routine
recommended polling time: (2) minutes.
extended self-test routine
recommended polling time: (24) minutes.
conveyance self-test routine
recommended polling time: (3) minutes.
sct capabilities: (0x0035)SCT Status supported.
sct feature control supported.
sct data table supported.

smart attributes data structure revision number: 16

vendor specific smart attributes with thresholds:

id#	attribute_name	flag	value	worst	thresh	type	updated	when_failed	raw_value
1	raw_read_error_rate	0x002f	100	100	000	pre-fail	always	-	0
5	reallocate_nand_blk_cnt	0x0032	100	100	010	old_age	always	-	0



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9	power_on_hours	0x0032	100	100	000	old_age	always	-	29401
12	power_cycle_count	0x0032	100	100	000	old_age	always	-	24
171	program_fail_count	0x0032	100	100	000	old_age	always	-	0
172	erase_fail_count	0x0032	100	100	000	old_age	always	-	0
173	ave_block-erase_count	0x0032	001	001	000	old_age	always	-	562
174	unexpected_power_loss_ct	0x0032	100	100	000	old_age	always	-	21
183	sata_interfac_downshift	0x0032	100	100	000	old_age	always	-	0
184	error_correction_count	0x0032	100	100	000	old_age	always	-	0
187	reported_uncorrect	0x0032	100	100	000	old_age	always	-	224
194	temperature_celsius	0x0022	065	051	000	old_age	always	-	35 (min/max 10/49)
196	reallocated_event_count	0x0032	100	100	000	old_age	always	-	0
197	current_pending_ecc_cnt	0x0032	100	100	000	old_age	always	-	0
198	offline_uncorrectable	0x0030	100	100	000	old_age	offline	-	0
199	udma_crc_error_count	0x0032	100	100	000	old_age	always	-	0
202	percent_lifetime_remain	0x0030	000	000	001	old_age	offline	failing_now	100
206	write_error_rate	0x000e	100	100	000	old_age	always	-	0
246	total_lbas_written	0x0032	100	100	000	old_age	always	-	496747924513
247	host_program_page_count	0x0032	100	100	000	old_age	always	-	18802895023
248	ftl_program_page_count	0x0032	100	100	000	old_age	always	-	67182665143
180	unused_reserve_nand_blk	0x0033	000	000	000	pre-fail	always	-	4084
210	success_rain_recov_cnt	0x0032	100	100	000	old_age	always	-	6384

smart error log version: 1

ata error count: 224 (device log contains only the most recent five errors)

cr = command register [hex]

fr = features register [hex]

sc = sector count register [hex]

sn = sector number register [hex]

cl = cylinder low register [hex]

ch = cylinder high register [hex]

dh = device/head register [hex]

dc = device command register [hex]

er = error register [hex]

st = status register [hex]

powered_up_time is measured from power on, and printed as

ddd+hh:mm:ss.sss where DD=days, hh=hours, mm=minutes,

ss=sec, and sss=millisec. it "wraps" after 49.710 days.

error 224 occurred at disk power-on lifetime: 0 hours (0 days + 0 hours)

when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

40 51 00 67 90 95 e0 error: UNC at LBA = 0x00959067 = 9801831

commands leading to the command that caused the error were:

cr fr sc sn cl ch dh dc powered_up_time command/feature_name

-- -- -- -- --

42 00 00 67 90 95 e0 00 28d+08:04:04.896 READ VERIFY SECTOR(S) EXT

42 00 01 66 90 95 e0 00 28d+08:04:04.896 READ VERIFY SECTOR(S) EXT

35 00 01 66 90 95 e0 00 28d+08:04:04.896 WRITE DMA EXT

42 00 00 67 90 95 e0 00 28d+08:04:04.896 READ VERIFY SECTOR(S) EXT

42 00 01 66 90 95 e0 00 28d+08:04:04.896 READ VERIFY SECTOR(S) EXT

error 223 occurred at disk power-on lifetime: 0 hours (0 days + 0 hours)

when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

40 51 00 66 90 95 e0 error: UNC at LBA = 0x00959066 = 9801830

commands leading to the command that caused the error were:



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cr	fr	sc	sn	cl	ch	dh	dc	powered_up_time	command/feature_name
42	00	00	66	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
42	00	01	65	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
35	00	01	65	90	95	e0	00	28d+08:04:04.896	WRITE DMA EXT
42	00	00	66	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
42	00	01	65	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT

error 222 occurred at disk power-on lifetime: 0 hours (0 days + 0 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

40 51 00 65 90 95 e0 error: UNC at LBA = 0x00959065 = 9801829

commands leading to the command that caused the error were:

cr	fr	sc	sn	cl	ch	dh	dc	powered_up_time	command/feature_name
42	00	00	65	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
42	00	01	64	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
35	00	01	64	90	95	e0	00	28d+08:04:04.896	WRITE DMA EXT
42	00	00	65	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
42	00	01	64	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT

error 221 occurred at disk power-on lifetime: 0 hours (0 days + 0 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

40 51 00 64 90 95 e0 error: UNC at LBA = 0x00959064 = 9801828

commands leading to the command that caused the error were:

cr	fr	sc	sn	cl	ch	dh	dc	powered_up_time	command/feature_name
42	00	00	64	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
42	00	01	63	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
35	00	01	63	90	95	e0	00	28d+08:04:04.896	WRITE DMA EXT
42	00	00	64	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
42	00	01	63	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT

error 220 occurred at disk power-on lifetime: 0 hours (0 days + 0 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

40 51 00 63 90 95 e0 error: UNC at LBA = 0x00959063 = 9801827

commands leading to the command that caused the error were:

cr	fr	sc	sn	cl	ch	dh	dc	powered_up_time	command/feature_name
42	00	00	63	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
42	00	01	62	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
35	00	01	62	90	95	e0	00	28d+08:04:04.896	WRITE DMA EXT
42	00	00	62	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT
42	00	00	63	90	95	e0	00	28d+08:04:04.896	READ VERIFY SECTOR(S) EXT

smart self-test log structure revision number 1

num	test_description	status	remaining	lifetime(hours)	lba_of_first_error
# 1	vendor (0xff)	completed without error	00%	29208	-
# 2	vendor (0xff)	completed without error	00%	27384	-
# 3	vendor (0xff)	completed without error	00%	26904	-



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# 4	vendor (0xff)	completed without error	00%	26616	-
# 5	vendor (0xff)	completed without error	00%	26400	-
# 6	vendor (0xff)	completed without error	00%	25992	-
# 7	vendor (0xff)	completed without error	00%	25927	-
# 8	vendor (0xff)	completed without error	00%	16499	-
# 9	vendor (0xff)	completed without error	00%	1276	-
#10	vendor (0xff)	completed without error	00%	1131	-
#11	vendor (0xff)	completed without error	00%	145	-

smart selective self-test log data structure revision number 1

span	min_lba	max_lba	current_test_status
------	---------	---------	---------------------

1	0	0	not_testing
---	---	---	-------------

2	0	0	not_testing
---	---	---	-------------

3	0	0	not_testing
---	---	---	-------------

4	0	0	not_testing
---	---	---	-------------

5	0	0	not_testing
---	---	---	-------------

selective self-test flags (0x0):

after scanning selected spans, do not read-scan remainder of disk.

if selective self-test is pending on power-up, resume after 0 minute delay.